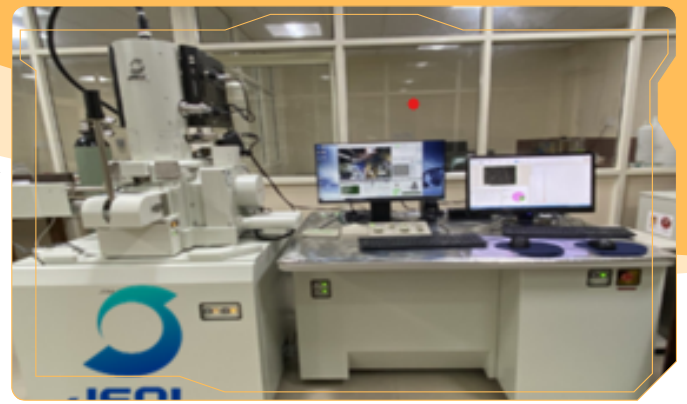




Sant Longowal Institute of
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CENTRAL FACILITY LAB

ADVANCED R&D EQUIPMENTS

FIELD EMISSION SCANNING ELECTRON MICROSCOPE (FESEM) & ENERGY DISPERSIVE SPECTROMETER (EDS) [JSM7610FPLUS]

JSM-7610F Plus is an ultra high resolution Schottky **Field Emission Scanning Electron Microscope** has semi-in-lens objective lens. High power optics can provide high throughput and high-performance analysis.

APPLICATIONS

- ✓ 3-D topographic imaging
- ✓ Micro structure of different materials (grain size, phase identification)
- ✓ Atomic contrast imaging by Retractable backscattered electron imaging (RBSEI) detector
- ✓ Topographic high resolution imaging of materials by Secondary electron Imaging (SEI) detector
- ✓ Gentle beam mode for soft materials (organic)
- ✓ Elemental distribution by EDS (spot/Line/area mapping)
- ✓ Quantification of elements by ZAF method with EDS system

✓ **RESOLUTION:**
0.8 nm (15 kV),
1.0 nm (kV GB mode)

✓ **MAGNIFICATION:**
25 - 1,000,000 X

✓ **DETECTOR:**
SEI, LEI & RBSEI

✓ **SPECIMEN STAGE:**
Eucentric, 5-Axis
Motor Control

✓ **TILT:**
-5° to + 70°

FESEM Samples may be sent for
Analysis to: Prof. Harish Chopra,
CHAIRMAN, Central Facility Lab.,
Science Block, SLIET, Longowal -
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Contact Us



E-mail

centralfacility_lab@sliet.ac.in



Website (For details/Rates)

<http://sliet.ac.in/2020/06/circular-for-charges-for-testing-analysis-on-xrd-system/>